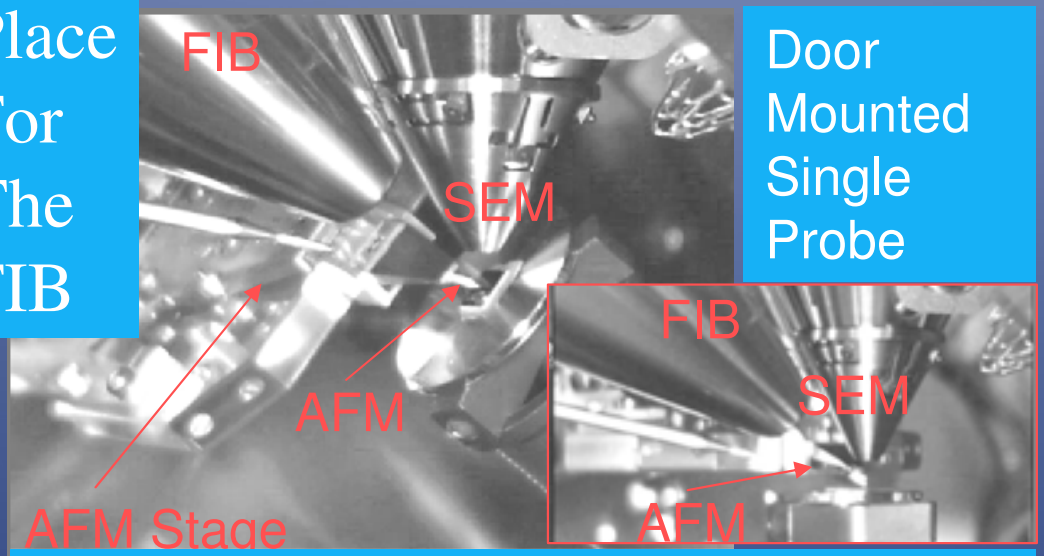
NANONICS IMAGING Ltd.

Integrated SPM With Electron & Ion Beam Microscopes

Leads To A New Synergy Of Measurement Options

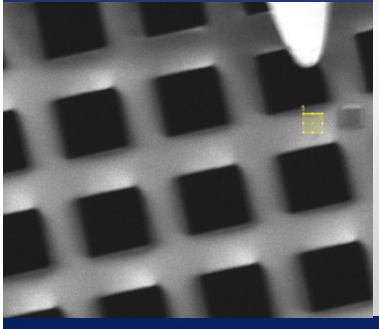
In Place For The FIB

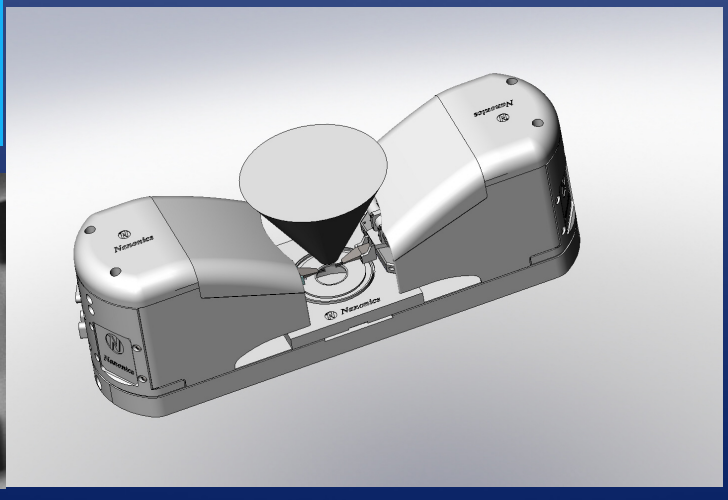


Door Mounted Single Probe

Rotated For SEM Imaging

Or A Stage Mounted Dual Probe Version





The Next Evolution in SPM™

MV 4000 SDB

- Probe & Stage Scanning (Door mounted only probe scanning)
- X & Y range 70 µ (Door mounted)
- X & Y range 150 µ (Stage mounted)
- Z range 35 µ (Door mounted)
- Z range 115 µ (Stage mounted)
- Sample Z autofocus to keep tip & sample in E beam focus (N/A door mounted)
- Standard AFM Probes & Indentors
- Unique electron/ion beam friendly cantilevers & NanoToolKit™ of SEM/FIB optimized probes with a variety of functionalities from electrical to thermal to near-field optical
- Tilted sample and probe view

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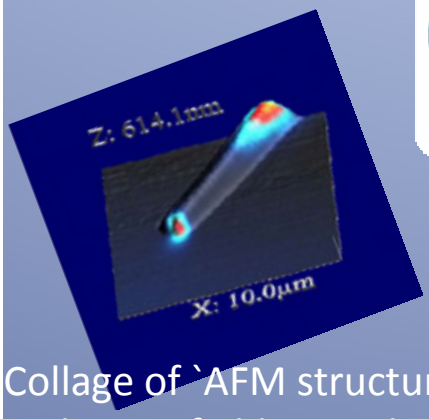
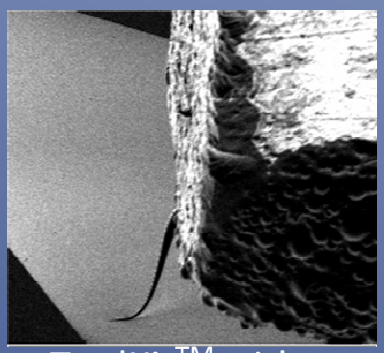


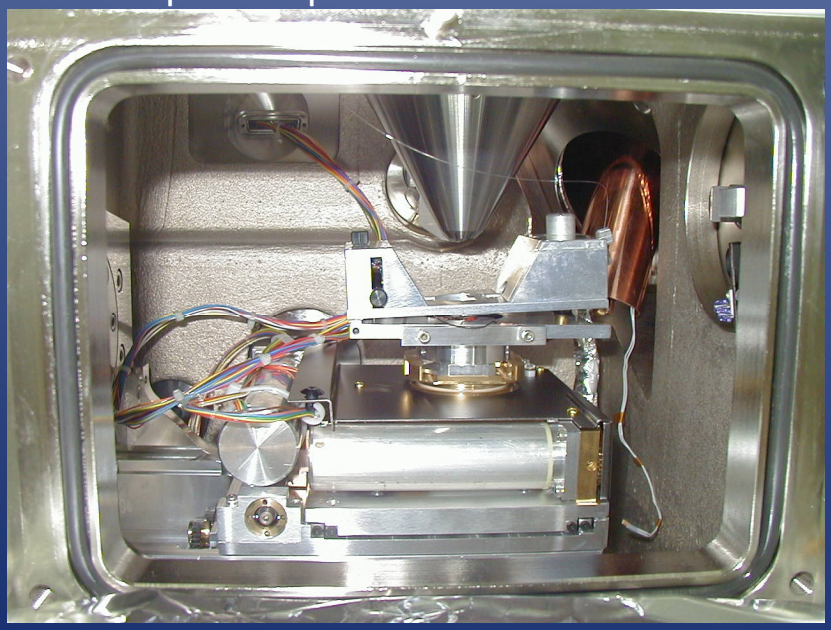
Collage of `AFM structure with near-field optical image of E Beam Excited Cathodoluminescence



NanoToolKit™ with a variety of functions of resistant to damage clear view probe tips

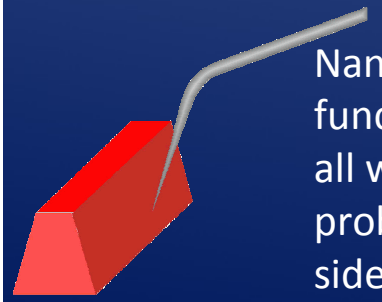
MV 2000 SDB

- Probe & Stage Scanning
- X & Y range 170 μ
- Z range 170 μ
- Sample Z autofocus to keep tip & sample in E beam focus
- Standard AFM Probes & Indentors
- Unique electron/ion beam friendly cantilevers & NanoToolKit™ of SEM/FIB optimized probes with a variety of functionalities from electrical to thermal to near-field optical
- Tilted sample and probe view

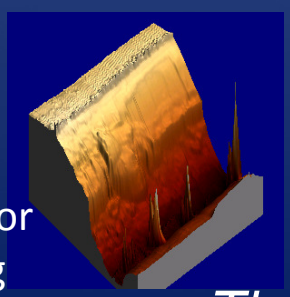


MV 1000 SDB

- Only stage scanning not probe scanning
- X & Y range 85 μ
- Z range 85 μ
- Sample Z autofocus to keep tip & sample in E beam focus
- Standard AFM Probes & Indentors
- Unique electron/ion beam friendly cantilevers & NanoToolKit™ of SEM/FIB optimized probes with a variety of functionalities from electrical to thermal to near-field optical
- Tilted sample and probe view



NanoToolKit™ functional probes all with exposed probe tips allow for side wall scanning



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